

Substitute for form 1449A/PTO				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Application Number	New Divisional Application
				Filing Date	June 26, 2003
				First Named Inventor	Shunpei YAMAZAKI et al.
				Art Unit	2815
				Examiner Name	G. Eckert, II
Sheet	1	of	2	Attorney Docket Number	740756-2626

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
		US-5,182,620	01/1993	Shimada et al.	
		US-5,739,549	04/1998	Takemura et al.	
		US-5,942,310	08/1999	Moon	
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FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁴
		Country Code ³ Number ⁴ Kind Code ⁵ (if known)				
		GB 2-307 326	05/1997	Shin et al.		

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS); title of the article (when appropriate); title of the item (book, magazine, journal, serial, symposium, catalog, etc.); date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		Shimokawa et al., "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", Japanese Journal of Applied Physics, Vol. 27, No. 5, May, 1988, pp. 751-758.	

Examiner Signature		Date Considered	4/2004
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.

Form PTO-1449 (Rev. 8-83)		U.S. Department of Commerce Patent and Trademark Office		Attorney Docket: 740756-2626		Serial No.	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				Applicant: Shunpei YAMAZAKI et al.			
				Filing Date: June 26, 2003		Group: 2815	
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date	
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	09-312260	12/02/1997	Japan			Abstract	
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	07-218932	08/18/1995	Japan			Abstract	
Examiner	Date Considered		4/2004				

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